

28th - 29th
August
2025

6th India ESD Workshop

Indian Institute of Science, Bangalore, India

India ESD Workshop (InEW)

ESD reliability understanding and how to design ESD safe chips have always been highly important and crucial aspects for semiconductor design, development, testing, and manufacturing cycles. Given the absence of ESD design/testing/technology knowledge, expertise, and awareness in India, in 2015 **Indian Institute of Science (IISc), Bangalore** started efforts for industry professionals and students, which today is called **India ESD Workshop (InEW)**. This conference has gathered significant interest and traction from the semiconductor industry professionals in India, with the potential to expand to other regions going forward. For example, the last edition attracted 250+ senior-level engineers from the semiconductor industry. The conference has also flourished due to its significant collaborations with industry leaders like Global Foundries, Samsung, NXP Semiconductors, Texas Instruments, Cadence, Infineon, Western Digital, Intel, Micron Technology, AOS, Synopsys, ST Microelectronics, Qualcomm, etc. The objective of the conference has always been to promote the knowledge, know-how, and expertise in ESD design, technology, and testing, in collaboration with global ESD experts. With the growing manufacturing requirements, manufacturing push in the country, upcoming fabs, an increasing number of chip design centers getting into full product cycles (full product developments), and an increasing number of chip design start-ups with efforts on end products, this expertise becomes more than relevant and justifies the need and growth of venues like InEW to continue and grow. With the current context, it would not be an exaggeration if the conference grows to 500+ professionals in the years to come.

Technical Focus

- Advanced CMOS: FinFET, Nanowire, Nanosheets
- Analog technologies: Bipolar, RF, HV & BCD
- Modeling & simulation for on-chip ESD
- ESD phenomena in MEMS
- Failure analysis, troubleshooting, Latch-up
- ESD Test methods, and correlation issues
- System-level ESD modeling and simulations
- ESD circuit modeling & simulations co-design
- ESD issues in 2.5D and 3D stacking and TSV
- ESD challenges in Automotive and avionics
- EOS failures in Modern System



Technical Symposia



Industry Sessions



Industry Interaction



Panel Discussion



Young Researchers Meet



Poster Session



Meet the Experts

Workshop Highlights

03 Plenary Talks

03 Keynote Talks

20 Invited Talks

10+ Platform Presentations

30+ Poster Presentations

300+ Attendees

Why Attend InEW 2025 ?

- Global Engagement
- Cutting-edge Discoveries
- Expansive Networking
- Present and Propel
- For Students: A Unique platform to learn & shine
- Relevance to the Global Community